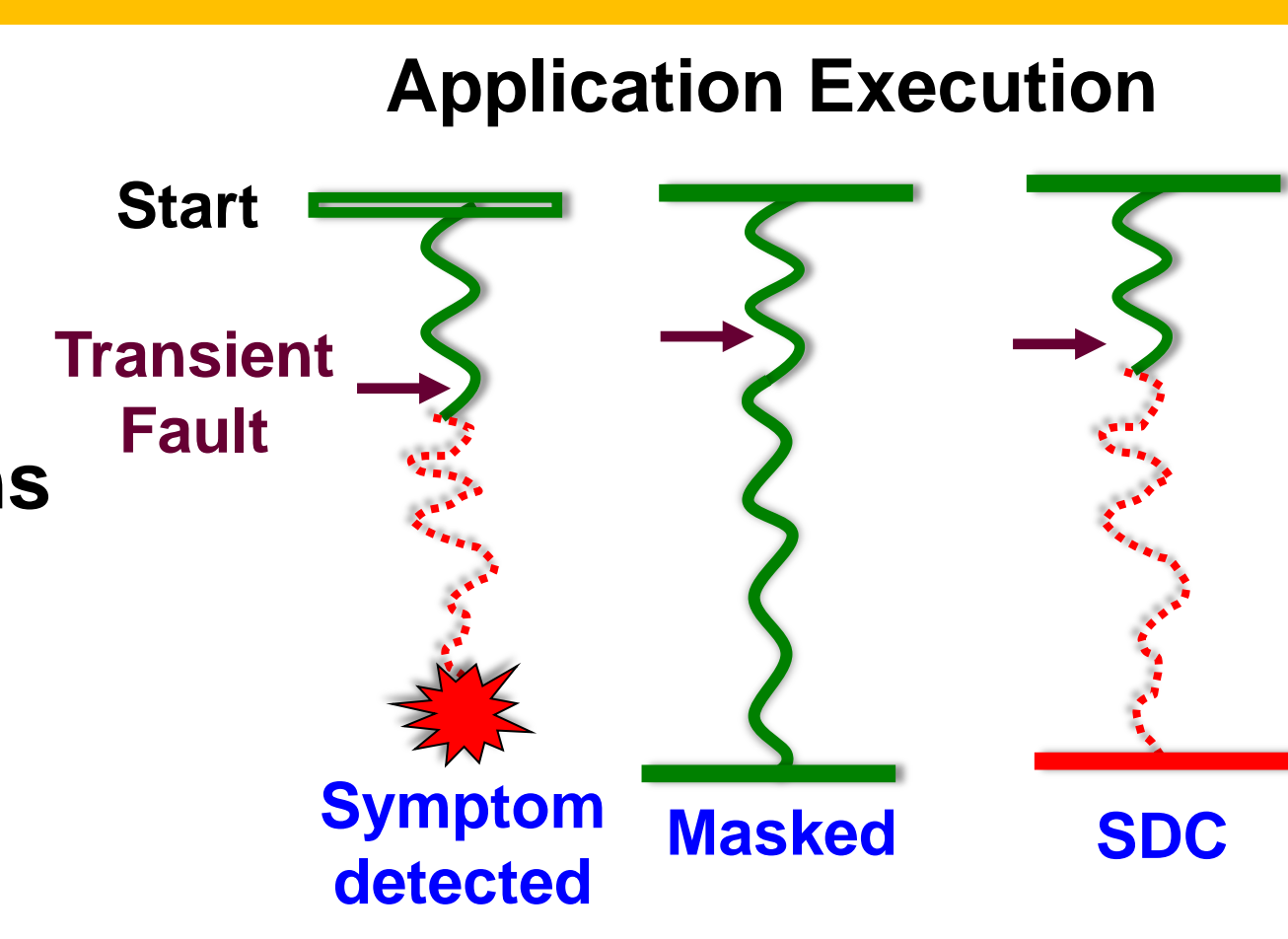


Motivation

Software anomaly detectors are low-cost and effective
Evaluated through statistical fault injection experiments
Limitations: Cannot provide guarantees
Cannot identify SDC-prone application sections

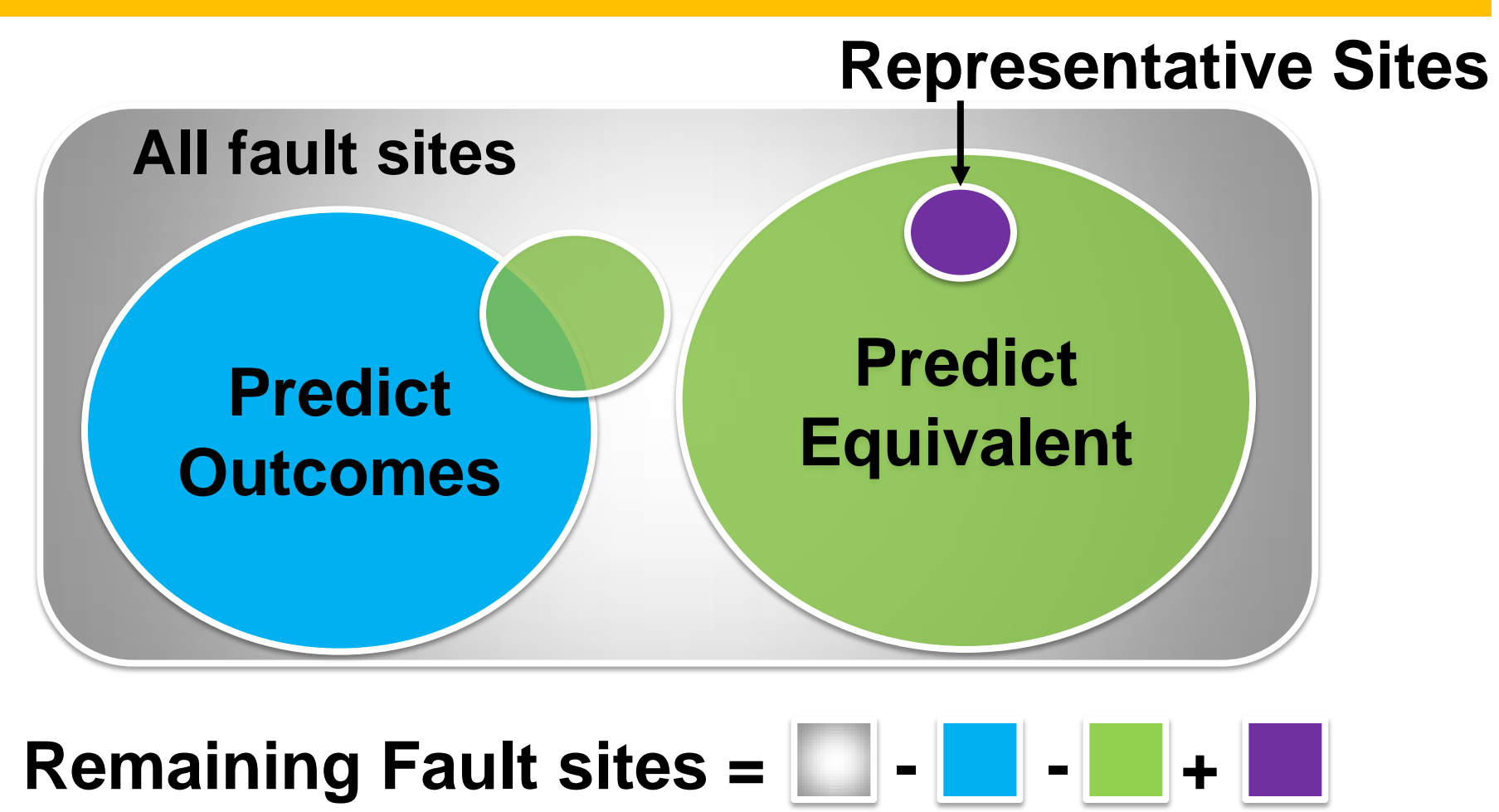
Goal: Analyzing all transient faults affecting an application
Advantages: Provide guarantees on detection mechanisms
List all SDC causing fault locations
Challenges: Do we need fault injections for all the faults?
How to analyze all faults with fewer fault injections?



Relyzer Overview

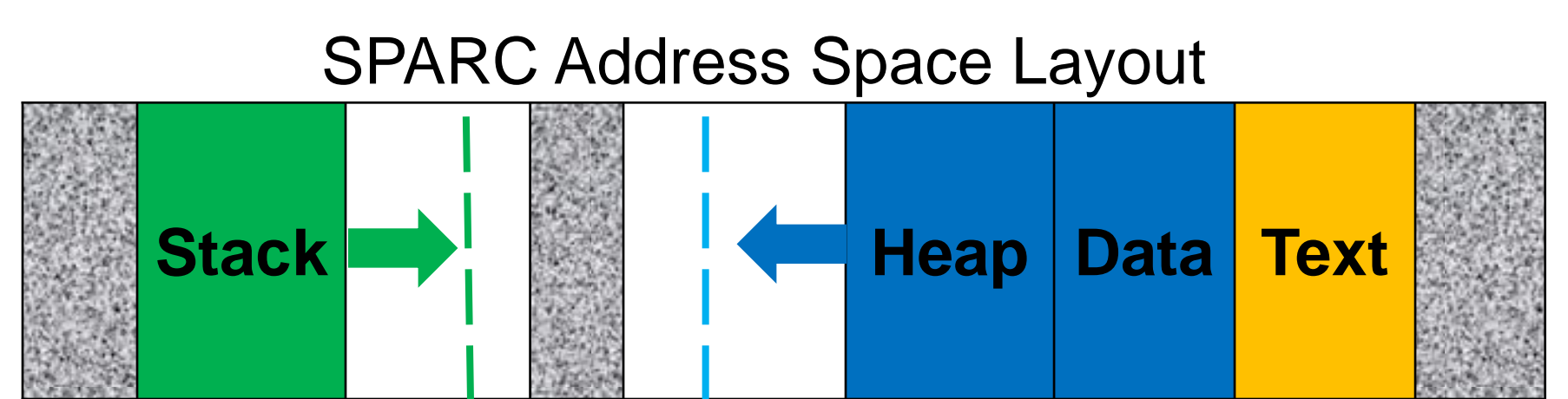
Fault Model: Transient bit flips in register operands of every executing instructions

Example: opcode rs1, rs2, rd
Fault sites: Single-bit flips in all bit locations of rs1, rs2, and rd



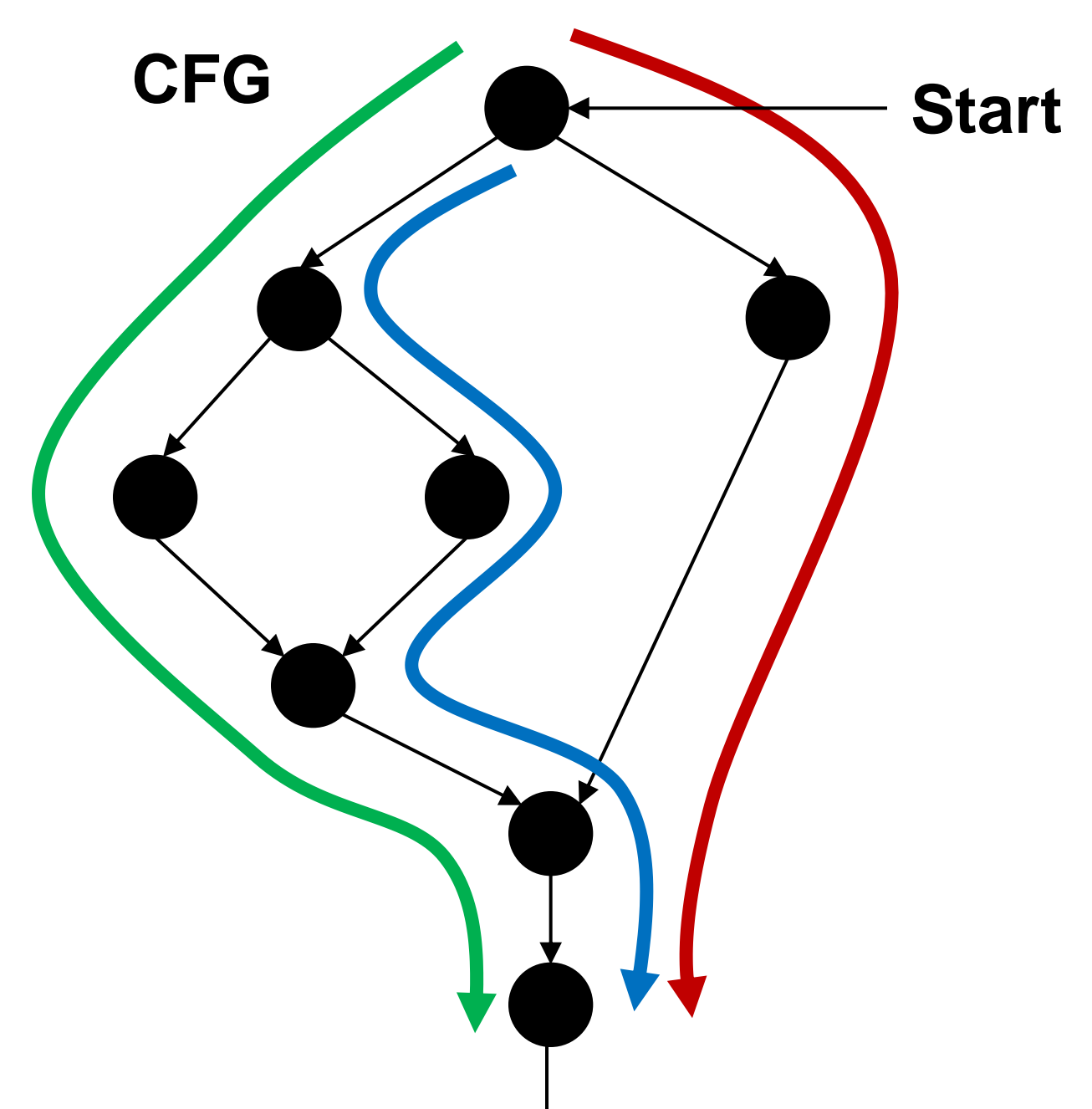
Fault Pruning Techniques

Determining Outcomes: Address Bounding
Prune out of bounds accesses
Memory addresses ([Blue] & [Green])
Branch targets ([Yellow])

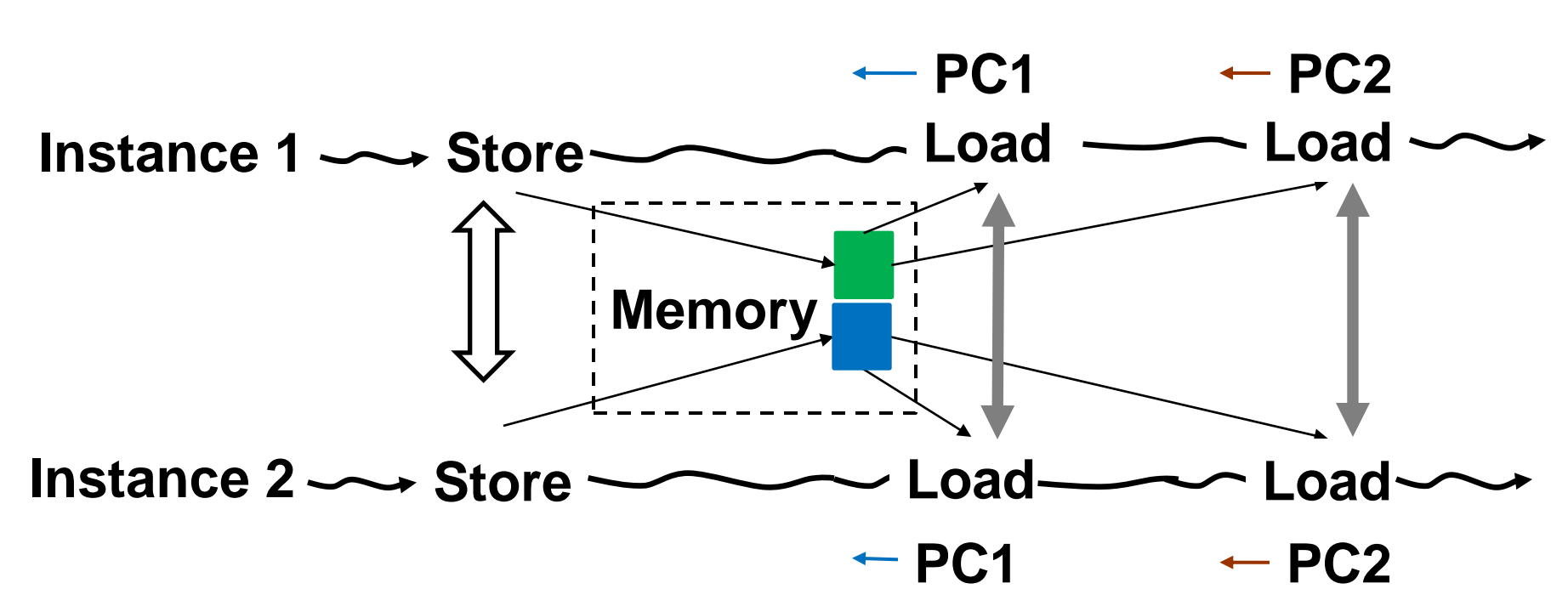


Predicting Equivalence: Control Analysis
Idea: Faults flowing through similar control paths may behave similarly

Example: Faults at *start* are categorized based on how they flow through the app

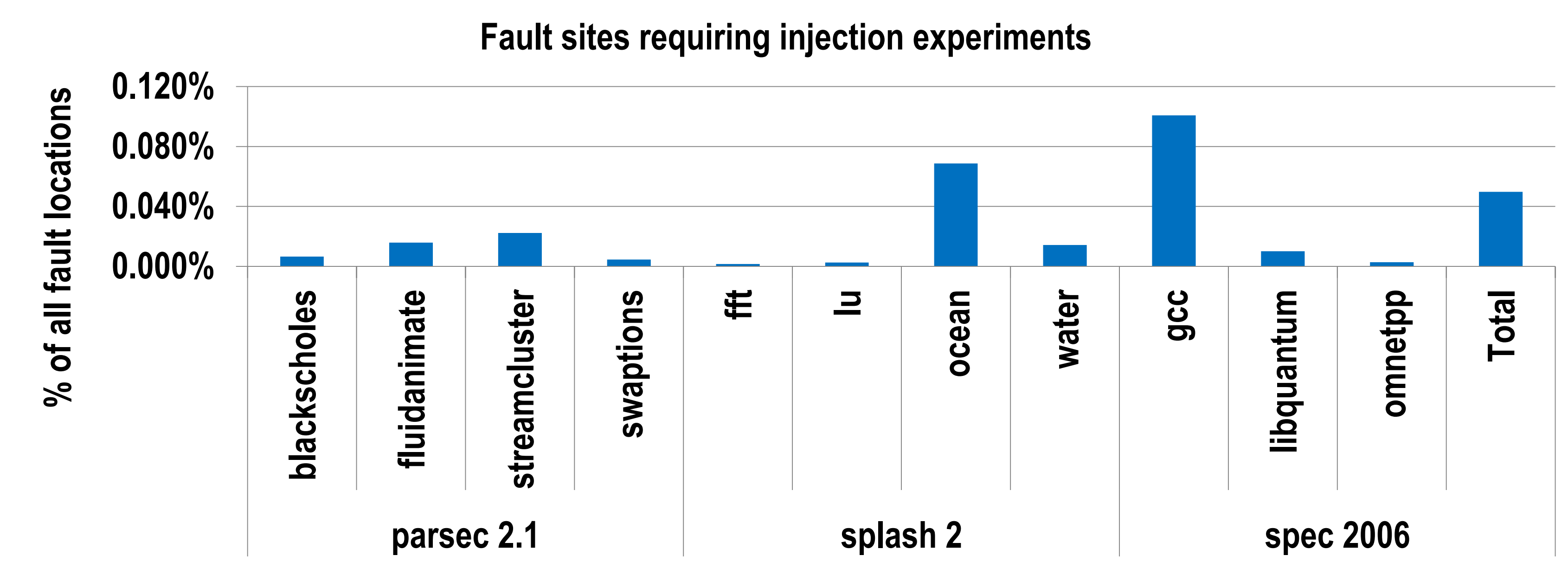


Predicting Equivalence: Store Analysis
Idea: Faults in store instructions may behave similarly if the value usage pattern is same



Pruning Results

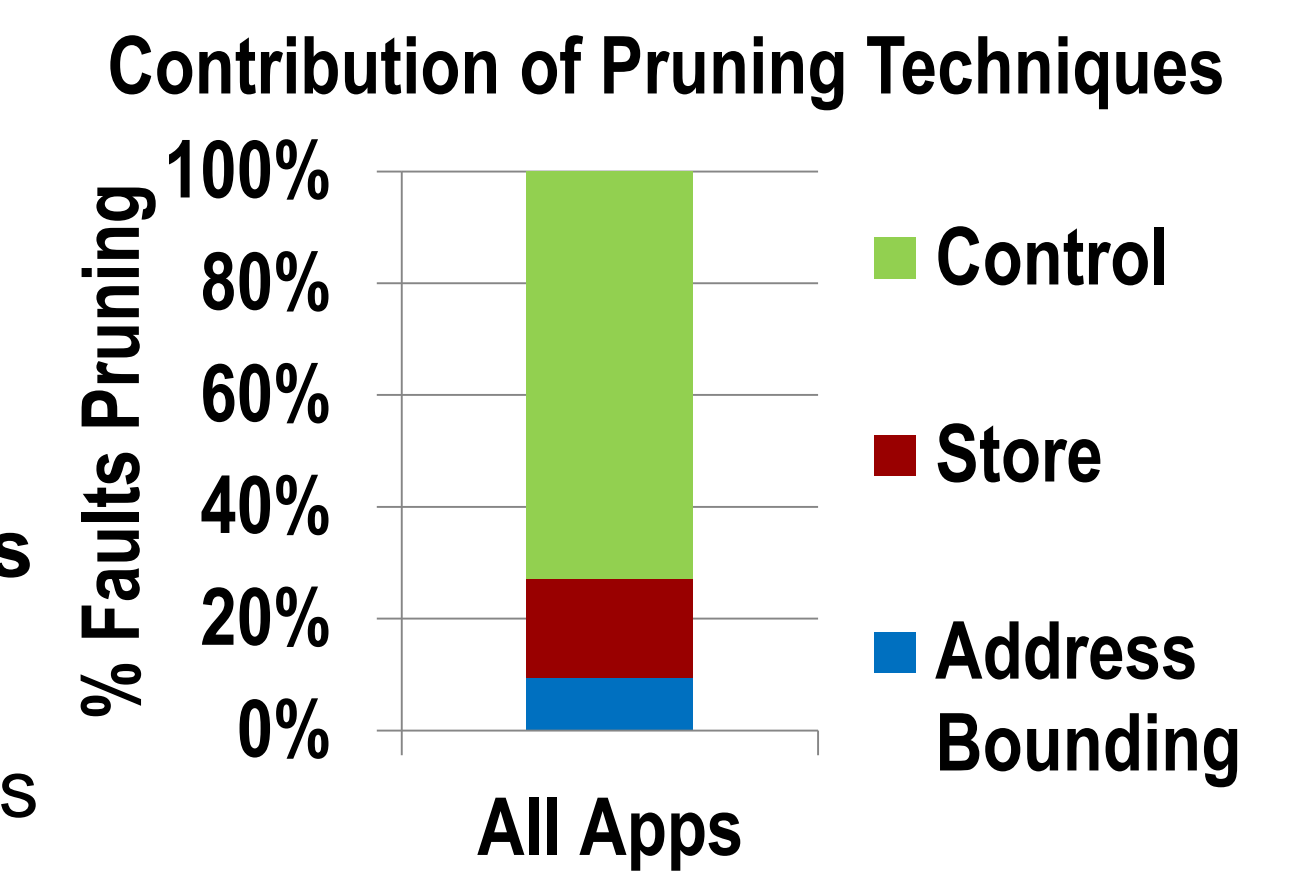
Total fault locations = 1.02 Billion



Total Remaining Faults (for 11 apps) = 505.9 Million

99% execution is represented by 42.5 Million fault sites

Injected faults in all the remaining fault sites for 6 applications
First study to analyze impact of all fault sites
Results are similar to high confidence random fault injections

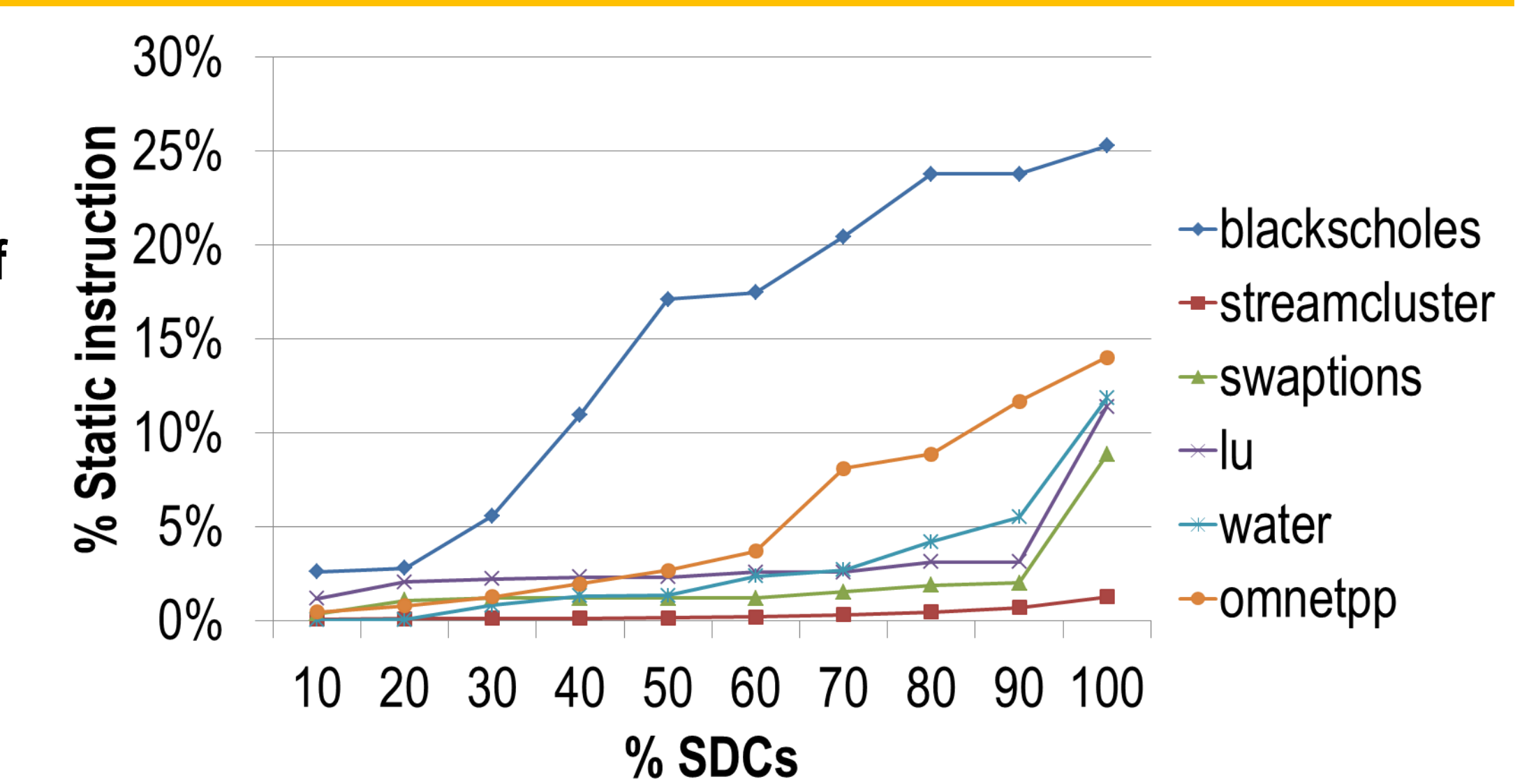


Finding SDC-causing Application Sites

Relyzer lists all the SDC causing sites

Over 90% of SDCs come from <18% of app instructions

Aids low-cost development of fault detectors



Conclusions and Future Work

Relyzer analyzes all application-level fault sites by studying fewer faults
Less than 0.005% fault sites require fault injections
Lists SDC causing application instructions

Understand application properties leading to SDCs
Thoroughly validate the pruning techniques
Develop low-cost application-level hardware fault detectors